

Notice of References Cited	Application/Control No. 10/812,526	Applicant(s)/Patent Under Reexamination LEE ET AL.	
	Examiner David J. Makiya	Art Unit 2885	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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*	B	US-6,507,049 B1	01-2003	Yeager et al.	257/100
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NON-PATENT DOCUMENTS

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